

Search Notes

Application/Control No.

10/614,409

Examiner

Y. Lee

Applicant(s)/Patent under
Reexamination

LIN ET AL.

Art Unit

2621

SEARCHED

Class	Subclass	Date	Examiner
375	240.01 240.16 240.25	11/22/2006	YL
348	425.4		
H04N	7/12		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR